

## A New Type of Inorganic Polymer with Ordered SiSiGe Sequences

Polysilanes and polygermanes are a new class of inorganic polymers based on linear backbones of catenated silicon atoms and germanium atoms, respectively. These polymers show remarkable properties such as photoconductivity,<sup>1-3</sup> highly efficient photoluminescence,<sup>4</sup> conductivity induced by chemical doping,<sup>5</sup> and third-order nonlinear effects.<sup>6,7</sup> Recently, a theoretical approach suggested that Si/Ge copolymers with ordered sequences corresponded to one-dimensional superlattice structures.<sup>8</sup> A one-dimensional superlattice would be of great scientific interest. However, a Wurtz type reaction of a mixture of organodichlorosilane and organodichlorogermane gives a random Si/Ge copolymer.<sup>9,10</sup> In this paper, we present a new idea that catenation of monomers with an SiGeSi sequence generates a periodic structure of SiSiGe sequences along a chain (Scheme I). This is the first report of the synthesis of a new type of inorganic polymer with ordered Si/Ge sequences.

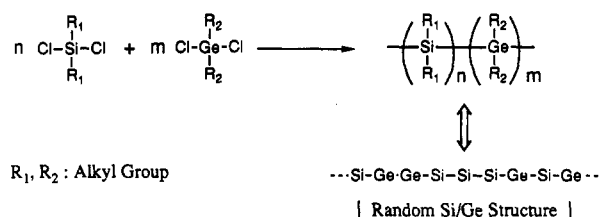
The new polymer was synthesized in a three-step process.<sup>11</sup> First, 10 g of sodium/potassium alloy (1:1 weight ratio) was dispersed in 300 mL of THF solution and refluxed. The mixture of 10.0 g (39 mmol) of di-*n*-butyl-dichlorogermane ( $\text{Bu}_2\text{GeCl}_2$ ) and 16.9 g (150 mmol) of trimethylchlorosilane ( $\text{Me}_3\text{SiCl}$ ) was added dropwise to the solution. After 3 h of reflux, the reaction mixture was filtered and the filtrate was distilled under reduced pressure. A total of 2.43 g (7.3 mmol) of bis(trimethylsilyl)di-*n*-butylgermane ( $(\text{Me}_3\text{Si})_2\text{GeBu}_2$ ) was obtained [yield: 18.9%, bp: 69 °C (0.3 mmHg)]. Second, 4 h of stirring of the mixture of 2.43 g of  $(\text{Me}_3\text{Si})_2\text{GeBu}_2$ , 10 g of  $\text{Me}_3\text{SiCl}$ , and anhydrous aluminum chloride as a catalyst at 48 °C gave 530 mg (1.4 mmol) of bis(dimethylchlorosilyl)di-*n*-butylgermane ( $(\text{Me}_2\text{ClSi})_2\text{GeBu}_2$ ) [yield: 19.2%, bp: 93 °C (0.5 mmHg)]. Third, 100 mg of sodium was dispersed in 10 mL of refluxed toluene. A total of 530 mg of  $(\text{Me}_2\text{ClSi})_2\text{GeBu}_2$  was added dropwise to the suspension and stirred for 3 h. The reaction mixture was filtered, and the filtrate was poured dropwise into excess ethanol. A total of 110 mg of polymer 1 was obtained (overall yield based on  $\text{Bu}_2\text{GeCl}_2$ : 0.94%).

For the characterization of polymer 1, two random copolymers consisting of Si and Ge were also prepared by the ordinary method (Scheme II). The mixture of 7.26 g (39 mmol) of 1,1,2,2-tetramethyl-1,2-dichlorodisilane ( $\text{ClMe}_2\text{SiSiMe}_2\text{Cl}$ ) and 10.0 g (39 mmol) of  $\text{Bu}_2\text{GeCl}_2$  and added dropwise to 150 mL of toluene including 4.3 g (197 mmol) of sodium dispersion. After 6 h of reflux, the reaction mixture was filtered and the filtrate was poured dropwise into excess ethanol. A total of 384 mg of poly(tetramethyldisilane-*ran*-di-*n*-butylgermane) (polymer 2) was obtained. Poly(dimethylsilane-*ran*-di-*n*-butylgermane) (polymer 3) was synthesized by a similar method using 10 g (77 mmol) of dimethyldichlorosilane ( $\text{Me}_2\text{SiCl}_2$ ), 10 g of  $\text{Bu}_2\text{GeCl}_2$ , and 6.0 g of sodium dispersion. A total of 390 mg of polymer 3 was obtained.

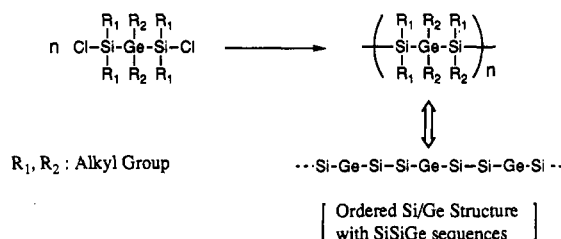
The resulting polymers were characterized by GPC, X-ray fluorescence analysis (XFA),<sup>12</sup> UV absorption,  $^1\text{H}$  NMR (200 MHz), and  $^{29}\text{Si}$  NMR (39 MHz). All NMR spectra were measured in tetrahydrofuran- $d_8$  at 20 °C. Table I shows the results of these analyses, and Figure 1 shows the  $^{29}\text{Si}$  NMR spectra. The atomic ratios (Si/Ge) of polymers 2 and 3 are quite different from the nominal compositions. In contrast, the atomic ratio (Si/Ge) of polymer 1 is 2.00, as expected from the procedure.

## Scheme I

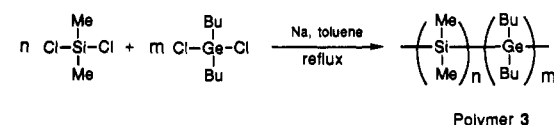
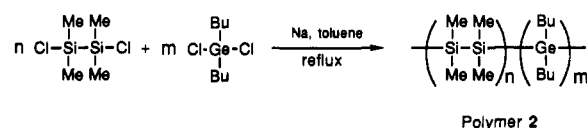
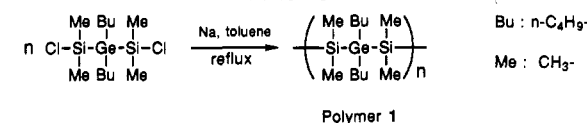
### Formation of Random Si/Ge Structure



### Formation of Ordered Si/Ge Structure



## Scheme II



In the  $^{29}\text{Si}$  NMR spectra, polymer 2 has two major multiple peaks near -38 and -29 ppm and polymer 3 has three near -37, -29, and -20 ppm. Two triad configurational sequences are predicted for polymer 2 (SiSi\*Si and SiSi\*Ge) and three for copolymer 3 (SiSi\*Si, SiSi\*Ge, and GeSi\*Ge). The results of  $^{29}\text{Si}$  NMR are consistent with this prediction. Since  $^{29}\text{Si}$  NMR chemical shifts for catenated silicon atoms with methyl substituents can be observed in the range of -36 to -40 ppm,<sup>13</sup> the peaks observed near -36 ppm in polymers 2 and 3 are assigned to Si\* with a SiSi\*Si triad configurational sequence. The peaks near -29 ppm and near -20 ppm are assigned to Si\* with SiSi\*Ge and GeSi\*Ge triad configurational sequences, respectively, because a germanium atom causes the signals of a nearby silicon atom to be shifted downfield. The  $^1\text{H}$  NMR spectra of polymers 2 and 3 also reflect the number of triad configurational sequences. Polymer 2 has two peaks that are assigned to  $\text{SiCH}_3$ , and polymer 3 has three. In addition, the multiplicity of the  $^{29}\text{Si}$  peaks shown in polymers 2 and 3 is attributed to several pentad configurational sequences such as SiGeSi\*SiGe and SiGeSi\*SiSi. These results mean that polymers 2 and 3 have random Si/Ge chain structures.

Table I

polymer <sup>a</sup>	nominal compos of Si/Ge (atomic ratio)	yields of polymer, %	mol wts (weight-averaged) <sup>c</sup>	atomic ratio of Si/Ge <sup>d</sup>	$\lambda_{\max}$ , <sup>e</sup> nm	<sup>1</sup> H NMR chemical shifts of SiCH <sub>3</sub> */ ppm from TMS
1	2.0 <sup>b</sup>	25.6	6 000	2.00	298.6	0.391
2	2.0	3.2	11 000	1.16	308.5	0.278 (1.0), 0.396 (0.8)
3	2.0	7.9	13 000	0.35	312.0	0.263 (1.0), 0.385 (0.8), 0.487 (0.8)

<sup>a</sup> All polymers were purified twice by reprecipitation with a toluene-ethanol system. Toluene-soluble fractions of polymers 2 and 3 were used in measurements. <sup>b</sup> Atomic ratio of the monomer. <sup>c</sup> Molecular weights were determined by GPC based on a polystyrene standard. <sup>d</sup> Compositional ratios were determined by XFA analysis. <sup>e</sup> UV spectra were measured in hexane at 25 °C. / TMS: tetramethylsilane. Values in parentheses are relative intensities.

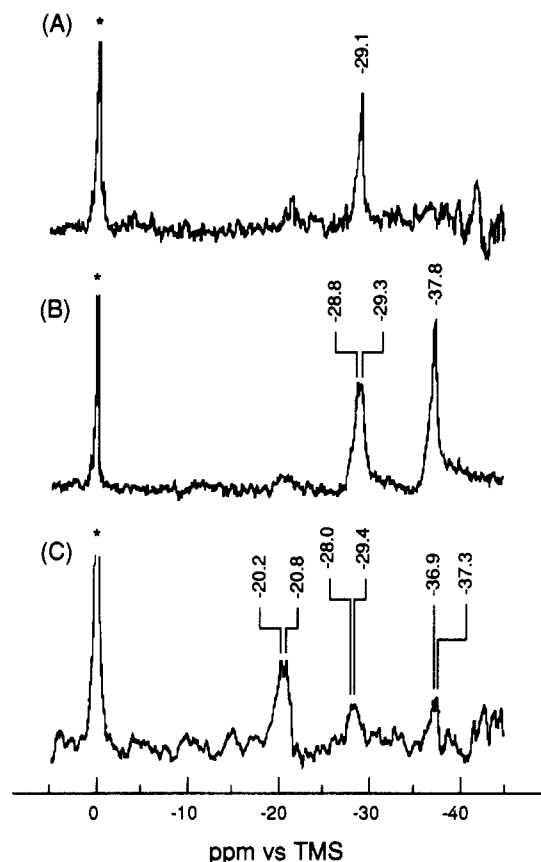


Figure 1. <sup>29</sup>Si NMR spectra (39 MHz) in tetrahydrofuran-*d*<sub>8</sub> at 20 °C of (a) polymer 1, (b) polymer 2, and (c) polymer 3. Asterisks indicate the tetramethylsilane internal signals.

In contrast, polymer 1 has one peak assigned to SiCH<sub>3</sub>\* at 0.391 ppm in the <sup>1</sup>H NMR spectrum and only one peak at -29.1 ppm in the <sup>29</sup>Si NMR spectrum. This peak in the <sup>29</sup>Si NMR is assigned to Si\* with an SiSi\*Ge triad configurational sequence because of the similar chemical shift to the peaks observed in polymers 2 and 3. The singularity of the <sup>29</sup>Si signal means that polymer 1 has only one type of pentad configurational sequence. There-

fore, polymer 1 consists of ordered SiSiGe sequences.

In summary, the present study shows that polymer 1 is in a periodic SiSiGe one-dimensional structure. Polymer 1 is the first example of a soluble one-dimensional superlattice. We are currently measuring the properties of these polymers, and they will be reported elsewhere.

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## References and Notes

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